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# Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	384
Number of Logic Elements/Cells	1728
Total RAM Bits	32768
Number of I/O	98
Number of Gates	57906
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv50-5tq144c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



# Virtex Device/Package Combinations and Maximum I/O

Table 3: Virtex Family Maximum User I/O by Device/Package (Excluding Dedicated Clock Pins)

Package	XCV50	XCV100	XCV150	XCV200	XCV300	XCV400	XCV600	XCV800	XCV1000
CS144	94	94							
TQ144	98	98							
PQ240	166	166	166	166	166				
HQ240						166	166	166	
BG256	180	180	180	180					
BG352			260	260	260				
BG432					316	316	316	316	
BG560						404	404	404	404
FG256	176	176	176	176					
FG456			260	284	312				
FG676						404	444	444	
FG680							512	512	512

# **Virtex Ordering Information**

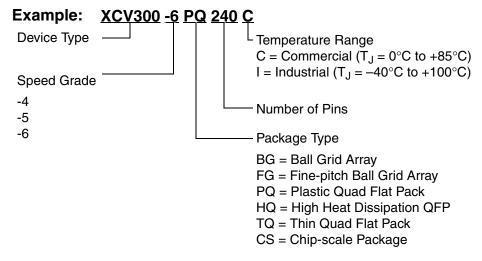


Figure 1: Virtex Ordering Information



#### Input Path

A buffer In the Virtex IOB input path routes the input signal either directly to internal logic or through an optional input flip-flop.

An optional delay element at the D-input of this flip-flop eliminates pad-to-pad hold time. The delay is matched to the internal clock-distribution delay of the FPGA, and when used, assures that the pad-to-pad hold time is zero.

Each input buffer can be configured to conform to any of the low-voltage signalling standards supported. In some of these standards the input buffer utilizes a user-supplied threshold voltage, V<sub>REF</sub>. The need to supply V<sub>REF</sub> imposes constraints on which standards can used in close proximity to each other. See I/O Banking, page 3.

There are optional pull-up and pull-down resistors at each user I/O input for use after configuration. Their value is in the range 50 k $\Omega$  – 100 k $\Omega$ .

#### **Output Path**

The output path includes a 3-state output buffer that drives the output signal onto the pad. The output signal can be routed to the buffer directly from the internal logic or through an optional IOB output flip-flop.

The 3-state control of the output can also be routed directly from the internal logic or through a flip-flip that provides synchronous enable and disable.

Each output driver can be individually programmed for a wide range of low-voltage signalling standards. Each output buffer can source up to 24 mA and sink up to 48mA. Drive strength and slew rate controls minimize bus transients.

In most signalling standards, the output High voltage depends on an externally supplied  $V_{CCO}$  voltage. The need to supply  $V_{CCO}$  imposes constraints on which standards can be used in close proximity to each other. See **I/O Banking**, page 3.

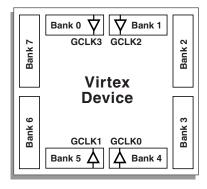
An optional weak-keeper circuit is connected to each output. When selected, the circuit monitors the voltage on the pad and weakly drives the pin High or Low to match the input signal. If the pin is connected to a multiple-source signal, the weak keeper holds the signal in its last state if all drivers are disabled. Maintaining a valid logic level in this way eliminates bus chatter.

Because the weak-keeper circuit uses the IOB input buffer to monitor the input level, an appropriate  $V_{\text{REF}}$  voltage must be provided if the signalling standard requires one. The provision of this voltage must comply with the I/O banking rules.

#### I/O Banking

Some of the I/O standards described above require  $V_{CCO}$  and/or  $V_{REF}$  voltages. These voltages externally and connected to device pins that serve groups of IOBs, called banks. Consequently, restrictions exist about which I/O standards can be combined within a given bank.

Eight I/O banks result from separating each edge of the FPGA into two banks, as shown in Figure 3. Each bank has multiple  $V_{\rm CCO}$  pins, all of which must be connected to the same voltage. This voltage is determined by the output standards in use.



X8778\_b

Figure 3: Virtex I/O Banks

Within a bank, output standards can be mixed only if they use the same  $V_{CCO}$ . Compatible standards are shown in Table 2. GTL and GTL+ appear under all voltages because their open-drain outputs do not depend on  $V_{CCO}$ .

Table 2: Compatible Output Standards

V <sub>CCO</sub>	Compatible Standards
3.3 V	PCI, LVTTL, SSTL3 I, SSTL3 II, CTT, AGP, GTL, GTL+
2.5 V	SSTL2 I, SSTL2 II, LVCMOS2, GTL, GTL+
1.5 V	HSTL I, HSTL III, HSTL IV, GTL, GTL+

Some input standards require a user-supplied threshold voltage,  $V_{REF}$  In this case, certain user-I/O pins are automatically configured as inputs for the  $V_{REF}$  voltage. Approximately one in six of the I/O pins in the bank assume this role

The  $V_{REF}$  pins within a bank are interconnected internally and consequently only one  $V_{REF}$  voltage can be used within each bank. All  $V_{REF}$  pins in the bank, however, must be connected to the external voltage source for correct operation.

Within a bank, inputs that require  $V_{REF}$  can be mixed with those that do not. However, only one  $V_{REF}$  voltage can be used within a bank. Input buffers that use  $V_{REF}$  are not 5 V tolerant. LVTTL, LVCMOS2, and PCI 33 MHz 5 V, are 5 V tolerant.

The  $V_{CCO}$  and  $V_{REF}$  pins for each bank appear in the device Pinout tables and diagrams. The diagrams also show the bank affiliation of each I/O.

Within a given package, the number of  $V_{REF}$  and  $V_{CCO}$  pins can vary depending on the size of device. In larger devices,



Each block SelectRAM cell, as illustrated in Figure 6, is a fully synchronous dual-ported 4096-bit RAM with independent control signals for each port. The data widths of the two ports can be configured independently, providing built-in bus-width conversion.

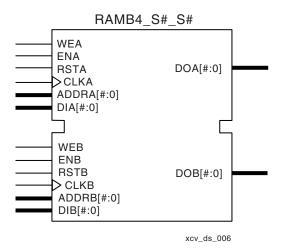


Figure 6: Dual-Port Block SelectRAM

Table 4 shows the depth and width aspect ratios for the block SelectRAM.

Table 4: Block SelectRAM Port Aspect Ratios

Width	Depth	ADDR Bus	Data Bus
1	4096	ADDR<11:0>	DATA<0>
2	2048	ADDR<10:0>	DATA<1:0>
4	1024	ADDR<9:0>	DATA<3:0>
8	512	ADDR<8:0>	DATA<7:0>
16	256	ADDR<7:0>	DATA<15:0>

The Virtex block SelectRAM also includes dedicated routing to provide an efficient interface with both CLBs and other block SelectRAMs. Refer to XAPP130 for block SelectRAM timing waveforms.

#### **Programmable Routing Matrix**

It is the longest delay path that limits the speed of any worst-case design. Consequently, the Virtex routing architecture and its place-and-route software were defined in a single optimization process. This joint optimization minimizes long-path delays, and consequently, yields the best system performance.

The joint optimization also reduces design compilation times because the architecture is software-friendly. Design cycles are correspondingly reduced due to shorter design iteration times.

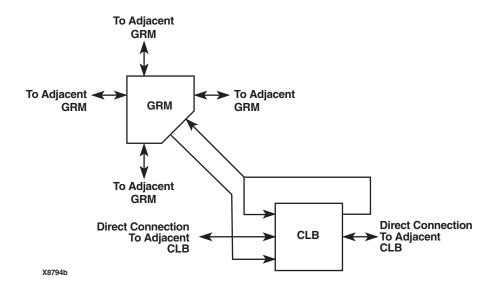


Figure 7: Virtex Local Routing

#### **Local Routing**

The VersaBlock provides local routing resources, as shown in Figure 7, providing the following three types of connections.

- Interconnections among the LUTs, flip-flops, and GRM
- Internal CLB feedback paths that provide high-speed connections to LUTs within the same CLB, chaining them together with minimal routing delay
- Direct paths that provide high-speed connections between horizontally adjacent CLBs, eliminating the delay of the GRM.



Four dedicated clock pads are provided, one adjacent to each of the global buffers. The input to the global buffer is

selected either from these pads or from signals in the general purpose routing.

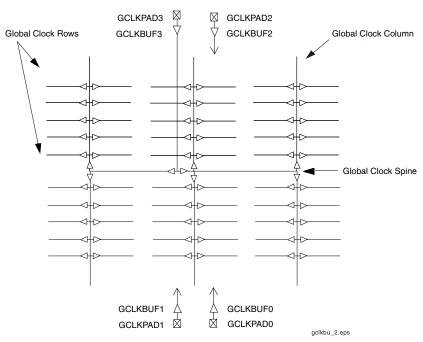


Figure 9: Global Clock Distribution Network

#### Delay-Locked Loop (DLL)

Associated with each global clock input buffer is a fully digital Delay-Locked Loop (DLL) that can eliminate skew between the clock input pad and internal clock-input pins throughout the device. Each DLL can drive two global clock networks. The DLL monitors the input clock and the distributed clock, and automatically adjusts a clock delay element. Clock edges reach internal flip-flops one to four clock periods after they arrive at the input. This closed-loop system effectively eliminates clock-distribution delay by ensuring that clock edges arrive at internal flip-flops in synchronism with clock edges arriving at the input.

In addition to eliminating clock-distribution delay, the DLL provides advanced control of multiple clock domains. The DLL provides four quadrature phases of the source clock, can double the clock, or divide the clock by 1.5, 2, 2.5, 3, 4, 5, 8, or 16.

The DLL also operates as a clock mirror. By driving the output from a DLL off-chip and then back on again, the DLL can be used to de-skew a board level clock among multiple Virtex devices.

In order to guarantee that the system clock is operating correctly prior to the FPGA starting up after configuration, the DLL can delay the completion of the configuration process until after it has achieved lock.

See **DLL Timing Parameters**, page 21 of Module 3, for frequency range information.

#### **Boundary Scan**

Virtex devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, INTEST, SAMPLE/PRELOAD, BYPASS, IDCODE, USERCODE, and HIGHZ instructions. The TAP also supports two internal scan chains and configuration/readback of the device.The TAP uses dedicated package pins that always operate using LVTTL. For TDO to operate using LVTTL, the  $\rm V_{CCO}$  for Bank 2 should be 3.3 V. Otherwise, TDO switches rail-to-rail between ground and  $\rm V_{CCO}$ .

Boundary-scan operation is independent of individual IOB configurations, and unaffected by package type. All IOBs, including un-bonded ones, are treated as independent 3-state bidirectional pins in a single scan chain. Retention of the bidirectional test capability after configuration facilitates the testing of external interconnections, provided the user design or application is turned off.

Table 5 lists the boundary-scan instructions supported in Virtex FPGAs. Internal signals can be captured during EXTEST by connecting them to un-bonded or unused IOBs. They can also be connected to the unused outputs of IOBs defined as unidirectional input pins.

Before the device is configured, all instructions except USER1 and USER2 are available. After configuration, all instructions are available. During configuration, it is recommended that those operations using the boundary-scan register (SAMPLE/PRELOAD, INTEST, EXTEST) not be performed.



# **Configuration**

Virtex devices are configured by loading configuration data into the internal configuration memory. Some of the pins used for this are dedicated configuration pins, while others can be re-used as general purpose inputs and outputs once configuration is complete.

The following are dedicated pins:

- Mode pins (M2, M1, M0)
- Configuration clock pin (CCLK)
- PROGRAM pin
- DONE pin
- Boundary-scan pins (TDI, TDO, TMS, TCK)

Depending on the configuration mode chosen, CCLK can be an output generated by the FPGA, or it can be generated externally and provided to the FPGA as an input. The PROGRAM pin must be pulled High prior to reconfiguration.

Note that some configuration pins can act as outputs. For correct operation, these pins can require a  $V_{CCO}$  of 3.3 V to permit LVTTL operation. All the pins affected are in banks 2 or 3. The configuration pins needed for SelectMap (CS, Write) are located in bank 1.

After Virtex devices are configured, unused IOBs function as 3-state OBUFTs with weak pull downs. For a more detailed description than that given below, see the XAPP138, Virtex Configuration and Readback.

#### **Configuration Modes**

Virtex supports the following four configuration modes.

- Slave-serial mode
- Master-serial mode
- SelectMAP mode
- · Boundary-scan mode

The Configuration mode pins (M2, M1, M0) select among these configuration modes with the option in each case of having the IOB pins either pulled up or left floating prior to configuration. The selection codes are listed in Table 7.

Configuration through the boundary-scan port is always available, independent of the mode selection. Selecting the boundary-scan mode simply turns off the other modes. The three mode pins have internal pull-up resistors, and default to a logic High if left unconnected. However, it is recommended to drive the configuration mode pins externally.

Table 7: Configuration Codes

Configuration Mode	M2	M1	МО	<b>CCLK Direction</b>	Data Width	Serial D <sub>out</sub>	Configuration Pull-ups
Master-serial mode	0	0	0	Out	1	Yes	No
Boundary-scan mode	1	0	1	N/A	1	No	No
SelectMAP mode	1	1	0	In	8	No	No
Slave-serial mode	1	1	1	In	1	Yes	No
Master-serial mode	1	0	0	Out	1	Yes	Yes
Boundary-scan mode	0	0	1	N/A	1	No	Yes
SelectMAP mode	0	1	0	In	8	No	Yes
Slave-serial mode	0	1	1	In	1	Yes	Yes

#### Slave-Serial Mode

In slave-serial mode, the FPGA receives configuration data in bit-serial form from a serial PROM or other source of serial configuration data. The serial bitstream must be setup at the DIN input pin a short time before each rising edge of an externally generated CCLK.

For more information on serial PROMs, see the PROM data sheet at:

http://www.xilinx.com/bvdocs/publications/ds026.pdf.

Multiple FPGAs can be daisy-chained for configuration from a single source. After a particular FPGA has been configured, the data for the next device is routed to the DOUT pin. The data on the DOUT pin changes on the rising edge of CCLK.

The change of DOUT on the rising edge of CCLK differs from previous families, but does not cause a problem for

mixed configuration chains. This change was made to improve serial configuration rates for Virtex-only chains.

Figure 12 shows a full master/slave system. A Virtex device in slave-serial mode should be connected as shown in the third device from the left.

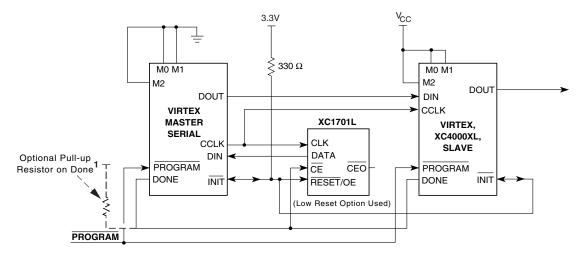
Slave-serial mode is selected by applying <111> or <011> to the mode pins (M2, M1, M0). A weak pull-up on the mode pins makes slave-serial the default mode if the pins are left unconnected. However, it is recommended to drive the configuration mode pins externally. Figure 13 shows slave-serial mode programming switching characteristics.

Table 8 provides more detail about the characteristics shown in Figure 13. Configuration must be delayed until the INIT pins of all daisy-chained FPGAs are High.



Table 8: Master/Slave Serial Mode Programming Switching

	Description	Figure References	Symbol	Values	Units
	DIN setup/hold, slave mode	1/2	T <sub>DCC</sub> /T <sub>CCD</sub>	5.0 / 0	ns, min
	DIN setup/hold, master mode	1/2	T <sub>DSCK</sub> /T <sub>CKDS</sub>	5.0 / 0	ns, min
	DOUT	3	T <sub>CCO</sub>	12.0	ns, max
CCLK	High time	4	T <sub>CCH</sub>	5.0	ns, min
OOLIK	Low time	5	T <sub>CCL</sub>	5.0	ns, min
	Maximum Frequency		F <sub>CC</sub>	66	MHz, max
	Frequency Tolerance, master mode with respect to nominal			+45% -30%	



Note 1: If none of the Virtex FPGAs have been selected to drive DONE, an external pull-up resistor of 330  $\Omega$  should be added to the common DONE line. (For Spartan-XL devices, add a 4.7K  $\Omega$  pull-up resistor.) This pull-up is not needed if the DriveDONE attribute is set. If used, DriveDONE should be selected only for the last device in the configuration chain.

xcv\_12\_050103

Figure 12: Master/Slave Serial Mode Circuit Diagram

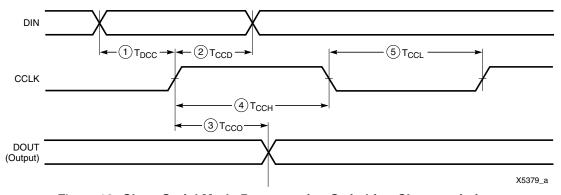


Figure 13: Slave-Serial Mode Programming Switching Characteristics

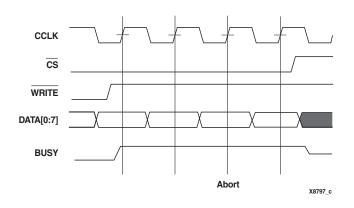


Figure 18: SelectMAP Write Abort Waveforms

#### Boundary-Scan Mode

In the boundary-scan mode, configuration is done through the IEEE 1149.1 Test Access Port. Note that the PROGRAM pin must be pulled High prior to reconfiguration. A Low on the PROGRAM pin resets the TAP controller and no JTAG operations can be performed.

Configuration through the TAP uses the CFG\_IN instruction. This instruction allows data input on TDI to be converted into data packets for the internal configuration bus.

The following steps are required to configure the FPGA through the boundary-scan port (when using TCK as a start-up clock).

- Load the CFG\_IN instruction into the boundary-scan instruction register (IR)
- 2. Enter the Shift-DR (SDR) state
- 3. Shift a configuration bitstream into TDI
- 4. Return to Run-Test-Idle (RTI)
- 5. Load the JSTART instruction into IR
- 6. Enter the SDR state
- 7. Clock TCK through the startup sequence
- 8. Return to RTI

Configuration and readback via the TAP is always available. The boundary-scan mode is selected by a <101> or 001> on the mode pins (M2, M1, M0). For details on TAP characteristics, refer to XAPP139.

#### **Configuration Sequence**

The configuration of Virtex devices is a three-phase process. First, the configuration memory is cleared. Next, configuration data is loaded into the memory, and finally, the logic is activated by a start-up process.

Configuration is automatically initiated on power-up unless it is delayed by the user, as described below. The configuration process can also be initiated by asserting  $\overline{\mathsf{PROGRAM}}$ .

The end of the memory-clearing phase is signalled by INIT going High, and the completion of the entire process is signalled by DONE going High.

The power-up timing of configuration signals is shown in Figure 19. The corresponding timing characteristics are listed in Table 10.

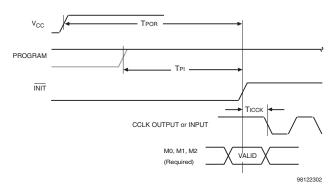


Figure 19: Power-Up Timing Configuration Signals

Table 10: Power-up Timing Characteristics

Description	Symbol	Value	Units
Power-on Reset	T <sub>POR</sub>	2.0	ms, max
Program Latency	T <sub>PL</sub>	100.0	μs, max
CCLK (output) Delay	T <sub>ICCK</sub>	0.5	μs, min
		4.0	μs, max
Program Pulse Width	T <sub>PROGRAM</sub>	300	ns, min

#### **Delaying Configuration**

INIT can be held Low using an open-drain driver. An open-drain is required since INIT is a bidirectional open-drain pin that is held Low by the FPGA while the configuration memory is being cleared. Extending the time that the pin is Low causes the configuration sequencer to wait. Thus, configuration is delayed by preventing entry into the phase where data is loaded.

#### Start-Up Sequence

The default Start-up sequence is that one CCLK cycle after DONE goes High, the global 3-state signal (GTS) is released. This permits device outputs to turn on as necessary.

One CCLK cycle later, the Global Set/Reset (GSR) and Global Write Enable (GWE) signals are released. This permits the internal storage elements to begin changing state in response to the logic and the user clock.

The relative timing of these events can be changed. In addition, the GTS, GSR, and GWE events can be made dependent on the DONE pins of multiple devices all going High, forcing the devices to start in synchronism. The sequence can also be paused at any stage until lock has been achieved on any or all DLLs.



# Virtex<sup>™</sup> 2.5 V Field Programmable Gate Arrays

DS003-3 (v4.0) March 1, 2013

**Production Product Specification** 

# Virtex Electrical Characteristics Definition of Terms

Electrical and switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

**Advance**: These speed files are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

**Preliminary**: These speed files are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

**Production**: These speed files are released once enough production silicon of a particular device family member has been characterized to provide full correlation between speed files and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications. Contact the factory for design considerations requiring more detailed information.

Table 1 correlates the current status of each Virtex device with a corresponding speed file designation.

Table 1: Virtex Device Speed Grade Designations

	Speed Grade Designations				
Device	Advance	Preliminary	Production		
XCV50			-6, -5, -4		
XCV100			-6, -5, -4		
XCV150			-6, -5, -4		
XCV200			-6, -5, -4		
XCV300			-6, -5, -4		
XCV400			-6, -5, -4		
XCV600			-6, -5, -4		
XCV800			-6, -5, -4		
XCV1000			-6, -5, -4		

All specifications are subject to change without notice.



### **Virtex DC Characteristics**

## **Absolute Maximum Ratings**

Symbol	Description <sup>(1)</sup>			Units
V <sub>CCINT</sub>	Supply voltage relative to GND <sup>(2)</sup>	Supply voltage relative to GND <sup>(2)</sup>		V
V <sub>CCO</sub>	Supply voltage relative to GND <sup>(2)</sup>		-0.5 to 4.0	V
V <sub>REF</sub>	Input Reference Voltage		-0.5 to 3.6	V
V	Input voltage relative to GND <sup>(3)</sup>	Using V <sub>REF</sub>	-0.5 to 3.6	V
V <sub>IN</sub>		Internal threshold	-0.5 to 5.5	V
V <sub>TS</sub>	Voltage applied to 3-state output		-0.5 to 5.5	V
V <sub>CC</sub>	Longest Supply Voltage Rise Time from 1V-2.375V		50	ms
T <sub>STG</sub>	Storage temperature (ambient)		-65 to +150	°C
TJ	Junction temperature <sup>(4)</sup>	Plastic Packages	+125	°C

#### Notes:

- Stresses beyond those listed under Absolute Maximum Ratings can cause permanent damage to the device. These are stress
  ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions
  is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time can affect device reliability.
- 2. Power supplies can turn on in any order.
- 3. For protracted periods (e.g., longer than a day),  $V_{IN}$  should not exceed  $V_{CCO}$  by more than 3.6 V.
- 4. For soldering guidelines and thermal considerations, see the "Device Packaging" information on <a href="https://www.xilinx.com">www.xilinx.com</a>.

## **Recommended Operating Conditions**

Symbol	Description		Min	Max	Units
V <sub>CCINT</sub> <sup>(1)</sup>	Input Supply voltage relative to GND, $T_J = 0$ °C to +85°C	Commercial	2.5 – 5%	2.5 + 5%	V
CCINT` /	Input Supply voltage relative to GND, $T_J = -40^{\circ}\text{C}$ to $+100^{\circ}\text{C}$	Industrial	2.5 – 5%	2.5 + 5%	V
V <sub>CCO</sub> <sup>(4)</sup>	Supply voltage relative to GND, T <sub>J</sub> = 0 °C to +85°C	Commercial	1.4	3.6	V
, CCO,	Supply voltage relative to GND, $T_J = -40^{\circ}C$ to $+100^{\circ}C$	Industrial	1.4	5% 2.5 + 5% 5% 2.5 + 5% 3.6	V
T <sub>IN</sub>	Input signal transition time			250	ns

#### Notes:

- Correct operation is guaranteed with a minimum V<sub>CCINT</sub> of 2.375 V (Nominal V<sub>CCINT</sub> -5%). Below the minimum value, all delay parameters increase by 3% for each 50-mV reduction in V<sub>CCINT</sub> below the specified range.
- 2. At junction temperatures above those listed as Operating Conditions, delay parameters do increase. Please refer to the TRCE report.
- 3. Input and output measurement threshold is  $\sim$ 50% of  $V_{CC}$ .
- Min and Max values for V<sub>CCO</sub> are I/O Standard dependant.



# **Virtex Switching Characteristics**

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation net list. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Virtex devices unless otherwise noted.

#### **IOB Input Switching Characteristics**

Input delays associated with the pad are specified for LVTTL levels. For other standards, adjust the delays with the values shown in , page 6.

				Speed	Grade		
Description	Device	Symbol	Min	-6	-5	-4	Units
Propagation Delays							
Pad to I output, no delay	All	T <sub>IOPI</sub>	0.39	0.8	0.9	1.0	ns, max
Pad to I output, with delay	XCV50	T <sub>IOPID</sub>	0.8	1.5	1.7	1.9	ns, max
	XCV100		0.8	1.5	1.7	1.9	ns, max
	XCV150		0.8	1.5	1.7	1.9	ns, max
	XCV200		0.8	1.5	1.7	1.9	ns, max
	XCV300		0.8	1.5	1.7	1.9	ns, max
	XCV400		0.9	1.8	2.0	2.3	ns, max
	XCV600		0.9	1.8	2.0	2.3	ns, max
	XCV800		1.1	2.1	2.4	2.7	ns, max
	XCV1000		1.1	2.1	2.4	2.7	ns, max
Pad to output IQ via transparent latch, no delay	All	T <sub>IOPLI</sub>	0.8	1.6	1.8	2.0	ns, max
Pad to output IQ via transparent	XCV50	T <sub>IOPLID</sub>	1.9	3.7	4.2	4.8	ns, max
latch, with delay	XCV100		1.9	3.7	4.2	4.8	ns, max
	XCV150		2.0	3.9	4.3	4.9	ns, max
	XCV200		2.0	4.0	4.4	5.1	ns, max
	XCV300		2.0	4.0	4.4	5.1	ns, max
	XCV400		2.1	4.1	4.6	5.3	ns, max
	XCV600		2.1	4.2	4.7	5.4	ns, max
	XCV800		2.2	4.4	4.9	5.6	ns, max
	XCV1000		2.3	4.5	5.1	5.8	ns, max
Sequential Delays			·				
Clock CLK	All						
Minimum Pulse Width, High		T <sub>CH</sub>	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low		T <sub>CL</sub>	0.8	1.5	1.7	2.0	ns, min
Clock CLK to output IQ		T <sub>IOCKIQ</sub>	0.2	0.7	0.7	8.0	ns, max



## **CLB Arithmetic Switching Characteristics**

Setup times not listed explicitly can be approximated by decreasing the combinatorial delays by the setup time adjustment listed. Precise values are provided by the timing analyzer.

		Speed Grade				
Description	Symbol	Min	-6	-5	-4	Units
Combinatorial Delays					•	•
F operand inputs to X via XOR	T <sub>OPX</sub>	0.37	0.8	0.9	1.0	ns, max
F operand input to XB output	T <sub>OPXB</sub>	0.54	1.1	1.3	1.4	ns, max
F operand input to Y via XOR	T <sub>OPY</sub>	0.8	1.5	1.7	2.0	ns, max
F operand input to YB output	T <sub>OPYB</sub>	0.8	1.5	1.7	2.0	ns, max
F operand input to COUT output	T <sub>OPCYF</sub>	0.6	1.2	1.3	1.5	ns, max
G operand inputs to Y via XOR	T <sub>OPGY</sub>	0.46	1.0	1.1	1.2	ns, max
G operand input to YB output	T <sub>OPGYB</sub>	0.8	1.6	1.8	2.1	ns, max
G operand input to COUT output	T <sub>OPCYG</sub>	0.7	1.3	1.4	1.6	ns, max
BX initialization input to COUT	T <sub>BXCY</sub>	0.41	0.9	1.0	1.1	ns, max
CIN input to X output via XOR	T <sub>CINX</sub>	0.21	0.41	0.46	0.53	ns, max
CIN input to XB	T <sub>CINXB</sub>	0.02	0.04	0.05	0.06	ns, max
CIN input to Y via XOR	T <sub>CINY</sub>	0.23	0.46	0.52	0.6	ns, max
CIN input to YB	T <sub>CINYB</sub>	0.23	0.45	0.51	0.6	ns, max
CIN input to COUT output	T <sub>BYP</sub>	0.05	0.09	0.10	0.11	ns, max
Multiplier Operation						•
F1/2 operand inputs to XB output via AND	T <sub>FANDXB</sub>	0.18	0.36	0.40	0.46	ns, max
F1/2 operand inputs to YB output via AND	T <sub>FANDYB</sub>	0.40	0.8	0.9	1.1	ns, max
F1/2 operand inputs to COUT output via AND	T <sub>FANDCY</sub>	0.22	0.43	0.48	0.6	ns, max
G1/2 operand inputs to YB output via AND	T <sub>GANDYB</sub>	0.25	0.50	0.6	0.7	ns, max
G1/2 operand inputs to COUT output via AND	T <sub>GANDCY</sub>	0.07	0.13	0.15	0.17	ns, max
Setup and Hold Times before/after Clock CLK <sup>(1)</sup>	Setup Time / Hold Time					•
CIN input to FFX	T <sub>CCKX</sub> /T <sub>CKCX</sub>	0.50 / 0	1.0 / 0	1.2 / 0	1.3 / 0	ns, min
CIN input to FFY	T <sub>CCKY</sub> /T <sub>CKCY</sub>	0.53 / 0	1.1 / 0	1.2 / 0	1.4 / 0	ns, min

#### Notes:

<sup>1.</sup> A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



# **Virtex Pin-to-Pin Output Parameter Guidelines**

All devices are 100% functionally tested. Listed below are representative values for typical pin locations and normal clock loading. Values are expressed in nanoseconds unless otherwise noted.

### Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, with DLL

			Speed Grade				
Description	Symbol	Device	Min	-6	-5	-4	Units
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, with DLL. For data output with different standards, adjust delays with the values shown in Output Delay Adjustments.	T <sub>ICKOFDLL</sub>	XCV50	1.0	3.1	3.3	3.6	ns, max
		XCV100	1.0	3.1	3.3	3.6	ns, max
		XCV150	1.0	3.1	3.3	3.6	ns, max
		XCV200	1.0	3.1	3.3	3.6	ns, max
		XCV300	1.0	3.1	3.3	3.6	ns, max
		XCV400	1.0	3.1	3.3	3.6	ns, max
		XCV600	1.0	3.1	3.3	3.6	ns, max
		XCV800	1.0	3.1	3.3	3.6	ns, max
		XCV1000	1.0	3.1	3.3	3.6	ns, max

#### Notes:

- 1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
- Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see Table 2 and Table 3.
- 3. DLL output jitter is already included in the timing calculation.

## Global Clock Input-to-Output Delay for LVTTL, 12 mA, Fast Slew Rate, without DLL

			Speed Grade				
Description	Symbol	Device	Min	-6	-5	-4	Units
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, without DLL. For data output with different standards, adjust delays with the values shown in Input and Output Delay Adjustments.  For I/O standards requiring V <sub>REF</sub> such as GTL, GTL+, SSTL, HSTL, CTT, and AGO, an additional 600 ps must be added.	T <sub>ICKOF</sub>	XCV50	1.5	4.6	5.1	5.7	ns, max
		XCV100	1.5	4.6	5.1	5.7	ns, max
		XCV150	1.5	4.7	5.2	5.8	ns, max
		XCV200	1.5	4.7	5.2	5.8	ns, max
		XCV300	1.5	4.7	5.2	5.9	ns, max
		XCV400	1.5	4.8	5.3	6.0	ns, max
		XCV600	1.6	4.9	5.4	6.0	ns, max
		XCV800	1.6	4.9	5.5	6.2	ns, max
		XCV1000	1.7	5.0	5.6	6.3	ns, max

#### Notes:

- Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
- 2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see Table 2 and Table 3.



Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages) (Continued)

Pin Name	Device	CS144	TQ144	PQ/HQ240
V <sub>REF</sub> , Bank 3	XCV50	H11, K12	60, 68	130, 144
(V <sub>REF</sub> pins are listed	XCV100/150	+ J10	+ 66	+ 133
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 126
the required device	XCV400	N/A	N/A	+ 147
and all smaller devices listed in the same	XCV600	N/A	N/A	+ 132
package.)	XCV800	N/A	N/A	+ 140
Within each bank, if input reference voltage is not required, all V <sub>REF</sub> pins are general I/O.				
V <sub>REF</sub> , Bank 4	XCV50	L8, L10	79, 87	97, 111
(V <sub>REF</sub> pins are listed	XCV100/150	+ N10	+ 81	+ 108
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 115
the required device and all smaller devices	XCV400	N/A	N/A	+ 94
listed in the same	XCV600	N/A	N/A	+ 109
package.)	XCV800	N/A	N/A	+ 101
Within each bank, if input reference voltage is not required, all V <sub>REF</sub> pins are general I/O.				
V <sub>REF</sub> , Bank 5	XCV50	L4, L6	96, 104	70, 84
(V <sub>REF</sub> pins are listed	XCV100/150	+ N4	+ 102	+ 73
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 66
the required device	XCV400	N/A	N/A	+ 87
and all smaller devices listed in the same package.)	XCV600	N/A	N/A	+ 72
	XCV800	N/A	N/A	+ 80
Within each bank, if input reference voltage is not required, all V <sub>REF</sub> pins are general I/O.				



Table 3: Virtex Pinout Tables (BGA) (Continued)

Pin Name	Device	BG256	BG352	BG432	BG560
V <sub>CCO</sub> , Bank 7	All	G4, H4	G23, K26, N23	A31, L28, L31	C32, D33, K33, N32, T33
V <sub>REF</sub> , Bank 0	XCV50	A8, B4	N/A	N/A	N/A
(VREF pins are listed incrementally. Connect all	XCV100/150	+ A4	A16,C19, C21	N/A	N/A
pins listed for both the required device and all smaller devices listed in the	XCV200/300	+ A2	+ D21	B19, D22, D24, D26	N/A
same package.)	XCV400	N/A	N/A	+ C18	A19, D20,
Within each bank, if input					D26, E23, E27
reference voltage is not required, all V <sub>REF</sub> pins are	XCV600	N/A	N/A	+ C24	+ E24
general I/O.	XCV800	N/A	N/A	+ B21	+ E21
	XCV1000	N/A	N/A	N/A	+ D29
V <sub>REF</sub> , Bank 1	XCV50	A17, B12	N/A	N/A	N/A
(VREF pins are listed incrementally. Connect all	XCV100/150	+ B15	B6, C9, C12	N/A	N/A
pins listed for both the required device and all smaller devices listed in the	XCV200/300	+ B17	+ D6	A13, B7, C6, C10	N/A
same package.) Within each bank, if input reference voltage is not	XCV400	N/A	N/A	+ B15	A6, D7, D11, D16, E15
required, all V <sub>REF</sub> pins are	XCV600	N/A	N/A	+ D10	+ D10
general I/O.	XCV800	N/A	N/A	+ B12	+ D13
	XCV1000	N/A	N/A	N/A	+ E7
V <sub>REF</sub> , Bank 2	XCV50	C20, J18	N/A	N/A	N/A
(V <sub>REF</sub> pins are listed incrementally. Connect all pins listed for both the	XCV100/150	+ F19	E2, H2, M4	N/A	N/A
required device and all smaller devices listed in the same package.)	XCV200/300	+ G18	+ D2	E2, G3, J2, N1	N/A
	XCV400	N/A	N/A	+ R3	G5, H4,
Within each bank, if input reference voltage is not					L5, P4, R1
required, all V <sub>REF</sub> pins are	XCV600	N/A	N/A	+ H1	+ K5
general I/O.	XCV800	N/A	N/A	+ M3	+ N5
	XCV1000	N/A	N/A	N/A	+ B3



Table 3: Virtex Pinout Tables (BGA) (Continued)

Pin Name	Device	BG256	BG352	BG432	BG560
V <sub>REF</sub> , Bank 7	XCV50	G3, H1	N/A	N/A	N/A
(V <sub>REF</sub> pins are listed	XCV100/150	+ D1	D26, G26,	N/A	N/A
incrementally. Connect all pins listed for both the			L26		
required device and all	XCV200/300	+ B2	+ E24	F28, F31,	N/A
smaller devices listed in the same package.)				J30, N30	
Within each bank, if input reference voltage is not required, all V <sub>REF</sub> pins are	XCV400	N/A	N/A	+ R31	E31, G31, K31, P31, T31
general I/O.	XCV600	N/A	N/A	+ J28	+ H32
	XCV800	N/A	N/A	+ M28	+ L33
	XCV1000	N/A	N/A	N/A	+ D31
GND	All	C3, C18, D4, D5, D9, D10, D11, D12, D16, D17, E4, E17, J4, J17, K4, K17, L4, L17, M4, M17, T4, T17, U4, U5, U9, U10, U11, U12, U16, U17, V3, V18	A1, A2, A5, A8, A14, A19, A22, A25, A26, B1, B26, E1, E26, H1, H26, N1, P26, W1, W26, AB1, AB26, AE1, AF2, AF5, AF8, AF13, AF19, AF22, AF25, AF26	A2, A3, A7, A9, A14, A18, A23, A25, A29, A30, B1, B2, B30, B31, C1, C31, D16, G1, G31, J1, J31, P1, P31, T4, T28, V1, V31, AC1, AC31, AE1, AE31, AH16, AJ1, AJ31, AK1, AK2, AK30, AK31, AL2, AL3, AL7, AL9 AL14, AL18 AL23, AL25, AL29, AL30	A1, A7, A12, A14, A18, A20, A24, A29, A32, A33, B1, B6, B9, B15, B23, B27, B31, C2, E1, F32, G2, G33, J32, K1, L2, M33, P1, P33, R32, T1, V33, W2, Y1, Y33, AB1, AC32, AD33, AE2, AG1, AG32, AH2, AJ33, AL32, AM3, AM7, AM11, AM19, AM25, AM28, AM33, AN1, AN2, AN5, AN10, AN14, AN16, AN20, AN22, AN27, AN33
GND <sup>(1)</sup>	All	J9, J10, J11, J12, K9, K10, K11, K12, L9, L10, L11, L12, M9, M10, M11, M12	N/A	N/A	N/A
No Connect	All	N/A	N/A	N/A	C31, AC2, AK4, AL3

#### Notes:

1. 16 extra balls (grounded) at package center.



Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

Pin Name	Device	FG256	FG456	FG676	FG680
V <sub>CCINT</sub>	All	C3, C14, D4, D13, E5, E12, M5, M12, N4, N13, P3, P14	E5, E18, F6, F17, G7, G8, G9, G14, G15, G16, H7, H16, J7, J16, P7, P16, R7, R16, T7, T8, T9, T14, T15, T16, U6, U17, V5, V18	G7, G20, H8, H19, J9, J10, J11, J16, J17, J18, K9, K18, L9, L18, T9, T18, U9, U18, V9, V10, V11, V16, V17, V18, W8, W19, Y7, Y20	AD5, AD35, AE5, AE35, AL5, AL35, AM5, AM35, AR8, AR9, AR15, AR16, AR24, AR25, AR31, AR32, E8, E9, E15, E16, E24, E25, E31, E32, H5, H35, J5, J35, R5, R35, T5, T35
V <sub>CCO</sub> , Bank 0	All	E8, F8	F7, F8, F9, F10 G10, G11	H9, H10, H11, H12, J12, J13	E26, E27, E29, E30, E33, E34
V <sub>CCO</sub> , Bank 1	All	E9, F9	F13, F14, F15, F16, G12, G13	H15, H16, H17, H18, J14, J15	E6, E7, E10, E11, E13, E14
V <sub>CCO</sub> , Bank 2	All	H11, H12	G17, H17, J17, K16, K17, L16	J19, K19, L19, M18, M19, N18	F5, G5, K5, L5, N5, P5
V <sub>CCO</sub> , Bank 3	All	J11, J12	M16, N16, N17, P17, R17, T17	P18, R18, R19, T19, U19, V19	AF5, AG5, AN5, AK5, AJ5, AP5
V <sub>CCO</sub> , Bank 4	All	L9. M9	T12, T13, U13, U14, U15, U16,	V14, V15, W15, W16, W17, W18	AR6, AR7, AR10, AR11, AR13, AR14
V <sub>CCO</sub> , Bank 5	All	L8, M8	T10, T11, U7, U8, U9, U10	V12, V13, W9,W10, W11, W12	AR26, AR27, AR29, AR30, AR33, AR34
V <sub>CCO</sub> , Bank 6	All	J5, J6	M7, N6, N7, P6, R6, T6	P9, R8, R9, T8, U8, V8	AF35, AG35, AJ35, AK35, AN35, AP35
V <sub>CCO</sub> , Bank 7	All	H5, H6	G6, H6, J6, K6, K7, L7	J8, K8, L8, M8, M9, N9	F35, G35, K35, L35, N35, P35
V <sub>REF</sub> Bank 0	XCV50	B4, B7	N/A	N/A	N/A
(VREF pins are listed	XCV100/150	+ C6	A9, C6, E8	N/A	N/A
incrementally. Connect all pins listed for both	XCV200/300	+ A3	+ B4	N/A	N/A
the required device and all smaller devices	XCV400	N/A	N/A	A12, C11, D6, E8, G10	
listed in the same package.) Within each bank, if	XCV600	N/A	N/A	+ B7	A33, B28, B30, C23, C24, D33
input reference voltage	XCV800	N/A	N/A	+ B10	+ A26
is not required, all V <sub>REF</sub> pins are general I/O.	XCV1000	N/A	N/A	N/A	+ D34



Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

Pin Name	Device	FG256	FG456	FG676	FG680
V <sub>REF</sub> Bank 1	XCV50	B9, C11	N/A	N/A	N/A
(VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices	XCV100/150	+ E11	A18, B13, E14	N/A	N/A
	XCV200/300	+ A14	+ A19	N/A	N/A
	XCV400	N/A	N/A	A14, C20, C21, D15, G16	N/A
listed in the same package.) Within each bank, if	XCV600	N/A	N/A	+ B19	B6, B8, B18, D11, D13, D17
input reference voltage	XCV800	N/A	N/A	+ A17	+ B14
is not required, all V <sub>REF</sub> pins are general I/O.	XCV1000	N/A	N/A	N/A	+ B5
V <sub>REF</sub> , Bank 2	XCV50	F13, H13	N/A	N/A	N/A
(V <sub>REF</sub> pins are listed	XCV100/150	+ F14	F21, H18, K21	N/A	N/A
incrementally. Connect all pins listed for both	XCV200/300	+ E13	+ D22	N/A	N/A
the required device and all smaller devices listed in the same package.) Within each bank, if	XCV400	N/A	N/A	F24, H23, K20, M23, M26	N/A
	XCV600	N/A	N/A	+ G26	G1, H4, J1, L2, V5, W3
input reference voltage	XCV800	N/A	N/A	+ K25	+ N1
is not required, all V <sub>REF</sub> pins are general I/O.	XCV1000	N/A	N/A	N/A	+ D2
V <sub>REF</sub> , Bank 3	XCV50	K16, L14	N/A	N/A	N/A
(V <sub>REF</sub> pins are listed	XCV100/150	+ L13	N21, R19, U21	N/A	N/A
incrementally. Connect all pins listed for both	XCV200/300	+ M13	+ U20	N/A	N/A
the required device and all smaller devices listed in the same package.) Within each bank, if	XCV400	N/A	N/A	R23, R25, U21, W22, W23	N/A
	XCV600	N/A	N/A	+ W26	AC1, AJ2, AK3, AL4, AR1, Y1
input reference voltage	XCV800	N/A	N/A	+ U25	+ AF3
is not required, all V <sub>REF</sub> pins are general I/O.	XCV1000	N/A	N/A	N/A	+ AP4



## PQ240/HQ240 Pin Function Diagram

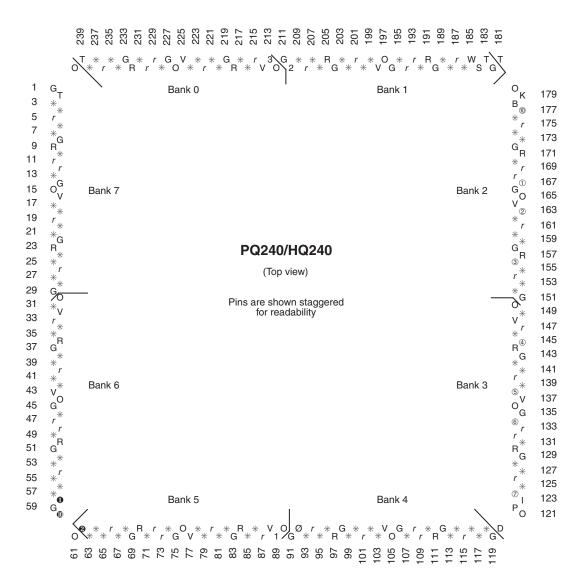


Figure 3: PQ240/HQ240 Pin Function Diagram



#### **BG256 Pin Function Diagram**

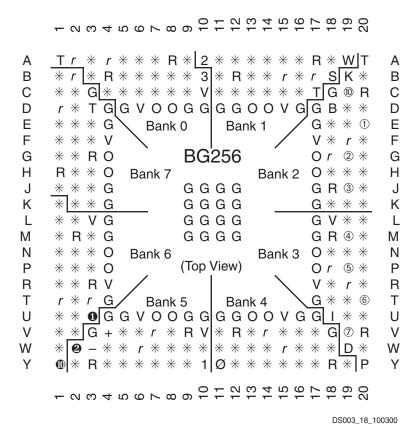
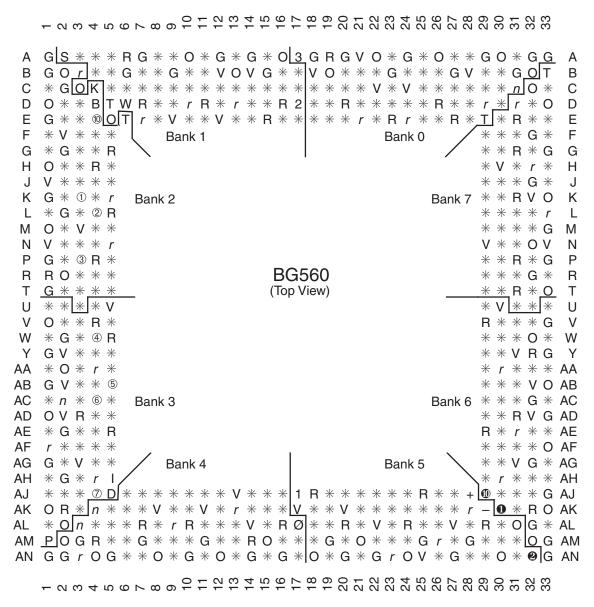


Figure 4: BG256 Pin Function Diagram



#### **BG560 Pin Function Diagram**



DS003\_22\_100300

Figure 7: BG560 Pin Function Diagram